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SCDS336C-NOVEMBER 2012-REVISED OCTOBER 2016

TS5A3159-Q1 1- Ω SPDT Analog Switch

Technical

Documents

1 Features

- · Qualified for Automotive Applications
- AEC-Q100 Qualified with the Following Results:
 - Device Temperature Grade 1: –40°C to +125°C Ambient Operating Temperature Range
 - Device HBM ESD Classification Level 2
 - Device CDM ESD Classification Level C4B
- Specified Break-Before-Make Switching
- Low ON-State Resistance (1 Ω)
- Control Inputs are 5-V Tolerant
- · Low Charge Injection
- Excellent ON-Resistance Matching
- · Low Total Harmonic Distortion
- 1.65-V to 5.5-V Single-Supply Operation

2 Applications

- · Automotive Infotainment and Cluster
- Body Electronics and Lighting

3 Description

Tools &

Software

The TS5A3159-Q1 is a single-pole double-throw (SPDT) analog switch that is designed to operate from 1.65 V to 5.5 V. The device offers a low ON-state resistance and an excellent ON-resistance, matching with the break-before-make feature to prevent signal distortion during the transferring of a signal from one channel to another. The device has an excellent total harmonic distortion (THD) performance and consumes very low power. These features make this device suitable for portable audio applications.

Support &

Community

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Device Information⁽¹⁾

PART NUMBER	PACKAGE	BODY SIZE (NOM)		
TS5A3159-Q1	SOT-23 (6)	2.90 mm × 4.00 mm		

(1) For all available packages, see the orderable addendum at the end of the datasheet.

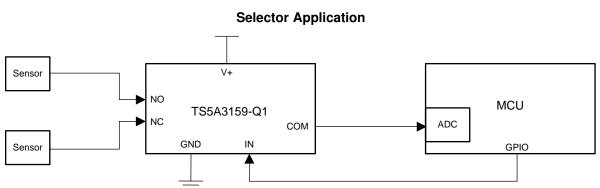


Table of Contents

1	Feat	tures 1
2	Арр	lications 1
3	Des	cription 1
4	Rev	ision History 2
5	Pin	Configuration and Functions 4
6	Spe	cifications 4
	6.1	Absolute Maximum Ratings 4
	6.2	ESD Ratings 4
	6.3	Recommended Operating Conditions 5
	6.4	Thermal Information 5
	6.5	Electrical Characteristics for 5-V Supply5
	6.6	Electrical Characteristics for 3.3-V Supply 6
	6.7	Electrical Characteristics For 2.5-V Supply8
	6.8	Electrical Characteristics For 1.8-V Supply9
	6.9	Typical Characteristics 10
7		ameter Measurement Information 12
8	Deta	ailed Description 17
	8.1	Overview 17

	8.2	Functional Block Diagram	17
	8.3	Feature Description	
	8.4	Device Functional Modes	17
9	Арр	lications and Implementation	18
	9.1	Application Information	
	9.2	Typical Application	
10		ver Supply Recommendations	
11	Lay	out	19
		Layout Guidelines	
		Layout Example	
12	Dev	ice and Documentation Support	20
	12.1		
	12.2	Receiving Notification of Documentation Updates	20
	12.3	Community Resources	20
	12.4	Trademarks	20
	12.5	Electrostatic Discharge Caution	20
	12.6	Glossary	20
13	Mec	hanical, Packaging, and Orderable	
	Info	mation	20

4 Revision History

2

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

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Cł	hanges from Revision B (October 2015) to Revision C	Page
•	Changed I/O for V ₊ from I to —	4
•	Added V _{NC} to Analog voltage, Analog port diode current, and ON-state switch current	4
•	Added Junction temperature, T _J to Absolute Maximum Ratings	4
•	Changed MIN value for V+ from 1.8 to 1.65 and MAX value from 5 to 5.5	5
•	Changed MAX value for IN from 5 to 5.5	5
•	Changed MAX value for NO, NC, COM from 5 to V+	5
•	Added V_{IL} MAX value 0.6 and deleted TYP value 0.6	7
•	Added Receiving Notification of Documentation Updates section	20

Changes from Revision A (December 2012) to Revision B

Changes from Original (November, 2012) to Revision A

- ---

•	Added ESD Ratings table, Feature Description section, Device Functional Modes, Application and Implementation
	section, Power Supply Recommendations section, Layout section, Device and Documentation Support section, and
	Mechanical, Packaging, and Orderable Information section

. . alway for OEOC from O and O to C. ~ • .

•	Change	d I _{NC(OFF)}	, I _{NO(OFF)}	min a	and max	value	es fo	or 25°	C from	–2 a	ind	d 2 to	o –6 a	nd 6, resp	ect	ivel	y. Chang	ged	min a	and
	max val	ues for F	ull from	–20 a	and 20 to	-150) an	ld 150	, respe	ective	ely									
	~							0500					~				~			

- Changed I_{NC(ON)}, I_{NO(ON)} min and max values for 25°C from -4 and 4 to -6 and 6, respectively. Changed min and max values for Full from -40 and 40 to -150 and 150, respectively...... 5
- Changed I_{COM(ON)} min and max values for 25°C from -4 and 4 to -8 and 8, respectively. Changed min and max values for Full from -40 and 40 to -150 and 150, respectively. 5

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4.7

Page

Page

5

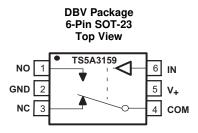


•	Changed max values for r _{peak} from 2.1 to 2.2	. 6
•	Changed max values for r _{on} from 1.5 to 1.8.	. 6
•	Added 25°C to T _A column and added 0.5 max value to I ₊	. 7
•	Changed r _{peak} max values from 2.7 to 2.9	. 8
•	Changed ron max values from 2 to 2.3.	. 8
•	Added 25°C to T _A column and added 0.5 max value to I ₊ .	. 8
•	Changed r _{peak} max values from 4.9 to 5.2	. 9
•	Changed r _{on} max values from 3.2 to 3.5.	. 9
•	Added 25°C to T _A column and added 0.5 max value to I ₊ .	. 9
•	Changed ON-state resistance from 1.1 to 1.3 Ω	17
•	Changd leakage current from ±20 nA to ±6 nA	17

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5 Pin Configuration and Functions



Pin Functions

1	PIN	I/O	DESCRIPTION			
NO.	NAME	1/O	DESCRIPTION			
1	NO	I/O	Normally-open terminal			
2	GND		Digital ground			
3	NC	I/O	Normally-closed terminal			
4	COM	I/O	Common terminal			
5	V ₊	_	ower supply			
6	IN	Ι	Digital control pin to connect COM terminal to NO or NC terminals			

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) ⁽¹⁾

			MIN	MAX	UNIT
V ₊	Supply voltage ⁽²⁾		-0.5	6.5	V
V_{NO}, V_{NC}, V_{COM}	Analog voltage ⁽²⁾⁽³⁾⁽⁴⁾		-0.5	V ₊ + 0.5	V
I _{I/OK}	Analog port diode current	V_{NO} , V_{NC} , $V_{COM} < 0$ or V_{NO} , V_{NC} , $V_{COM} > V_{+}$		±50	mA
I _{NO} , I _{NC} , I _{COM}	ON-state switch current	V_{NO} , V_{NC} , $V_{COM} = 0$ to V_+		±200	mA
	ON-state peak switch current ⁽⁵⁾			±400	mA
V _{IN}	Digital input voltage range ⁽²⁾⁽³⁾		-0.5	6.5	V
I _{IK}	Digital input clamp current	V _{IN} < 0		-50	mA
	Continuous current through V_+ or GND			±100	mA
TJ	Junction temperature			150	°C
T _{stg}	Storage temperature		-65	150	°C

(1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltages are with respect to ground, unless otherwise specified.

(3) The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

(4) This value is limited to 5.5 V maximum.

(5) Pulse at 1 ms duration < 10% duty cycle.

6.2 ESD Ratings

				VALUE	UNIT
V _(ESD)		Human body model (HBM), per AEC Q10	±2000		
	Electrostatic discharge	Charged device model (CDM), per AEC	Corner pins (NO, NC, IN, and COM)	±750	V
		Q100-011	Other pins	±500	

(1) AEC Q100-002 indicates HBM stressing is done in accordance with the ANSI/ESDA/JEDEC JS-001 specification.



6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

	MIN	MAX	UNIT
V+	1.65	5.5	V
IN	0	5.5	V
NO, NC, COM	0	V+	V

6.4 Thermal Information

		TS5A3159-Q1	
	THERMAL METRIC ⁽¹⁾	DBV (SOT-23)	UNIT
		6 PINS	
$R_{ heta JA}$	Junction-to-ambient thermal resistance	192.9	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	133.3	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	37.6	°C/W
ΨJT	Junction-to-top characterization parameter	38.9	°C/W
Ψ _{JB}	Junction-to-board characterization parameter	37.1	°C/W
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	N/A	°C/W

(1) For more information about traditional and new thermal metrics, see the *Semiconductor and IC Package Thermal Metrics* application report.

6.5 Electrical Characteristics for 5-V Supply

 $V_{+} = 4.5$ V to 5.5 V and $T_{A} = -40^{\circ}$ C to $+125^{\circ}$ C (unless otherwise noted)

	PARAMETER	TEST CONDI	TIONS	T _A	V.	MIN	TYP ⁽¹⁾	MAX	UNIT
ANALOG	SWITCH			I					
V _{COM} , V _{NO} ,V _{NC}	Analog signal range					0		V_{+}	V
	Peak ON resistance	$0 \le V_{NO}$ or $V_{NC} \le V_+$,	Switch ON,	25°C	4.5 V		1	1.5	Ω
r _{peak}	Feak ON resistance	$I_{COM} = -30 \text{ mA}$	See Figure 11	Full	4.5 V			1.5	12
	ON-state resistance	V_{NO} or $V_{NC} = 2.5 V$,	Switch ON,	25°C	4.5 V		0.75	1.3	Ω
r _{on}	ON-SIGLE TESISIGNCE	$I_{COM} = -30 \text{ mA}$	See Figure 10	Full	4.5 V			1.3	12
Δr_{on}	ON-state resistance match between channels	V_{NO} or V_{NC} = 2.5 V, I_{COM} = -30 mA	Switch ON, See Figure 10	25°C	4.5 V		0.1		Ω
		$0 \le V_{NO} \text{ or } V_{NC} \le V_+,$ $I_{COM} = -30 \text{ mA}$	Switch ON,	25°C	45.1		0.233		
r _{on(flat)}	ON-state resistance flatness	V_{NO} or V_{NC} = 1 V, 1.5 V, 2.5 V, I_{COM} = –30 mA	See Figure 10	25°C	4.5 V		0.15		Ω
I _{NC(OFF)} ,	NC, NO	V_{NC} or $V_{NO} = 4.5 V$,	Switch OFF,	25°C	5.5 V	-6	0.2	6	nA
I _{NO(OFF)}	OFF leakage current	$V_{COM} = 0$	See Figure 12	Full	5.5 V	-150		150	nA
I _{NC(ON)} ,	NC, NO	V_{NC} or $V_{NO} = 4.5 V$,	Switch ON,	25°C	5.5 V	-6	2.8	6	nA
I _{NO(ON)}	ON leakage current	VCOM = Open	See Figure 13	Full	5.5 V	-150		150	nA
	СОМ	V_{NC} or $V_{NO} = 4.5$ V or Open,	Switch ON,	25°C	5.5 V	-8	0.47	8	nA
I _{COM(ON)}	ON leakage current	$V_{COM} = 4.5 V$	See Figure 13	Full	5.5 V	-150		150	nA
DIGITAL I	NPUTS (IN)								
V _{IH}	Input logic high			Full		2.4		5.5	V
V _{IL}	Input logic low			Full		0		0.8	V
I _{IH} , I _{IL}	Input leakage current	V _{IN} = 5.5 V or 0		Full	5.5 V	-1		1	μA

(1) $T_A = 25^{\circ}C$

STRUMENTS

EXAS

Electrical Characteristics for 5-V Supply (continued)

$V_{\scriptscriptstyle +}$ = 4.5 V to 5.5 V and $T_{\sf A}$ = -40°C to +125°C (unless otherwise noted)

	PARAMETER	TEST CON	IDITIONS	TA	V.	MIN	TYP ⁽¹⁾	MAX	UNIT
DYNAMIC		L.							
•	Turn-on time	$V_{COM} = V_+,$	C _L = 35 pF,	25°C	4.5 V to		20	35	
t _{on}	rum-on lime	$R_L = 50 \Omega$,	See Figure 15	Full	5.5 V			40	ns
t	Turn-off time	$V_{COM} = V_+,$	C _L = 35 pF,	25°C	4.5 V to		15	20	ns
t _{OFF}		$R_L = 50 \Omega$,	See Figure 15	Full	5.5 V			35	115
t	Break-before-make time	$V_{NC} = V_{NO} = V_{+} / 2,$	C _L = 35 pF,	25°C	4.5 V to	1	12	14.5	ns
t _{BBM}		$R_L = 50 \Omega$,	See Figure 16	Full	5.5 V	1			113
Q _C	Charge injection	$C_L = 1 \text{ nF}, V_{GEN} = 0 \text{ V},$	See Figure 19	25°C	5 V		36		рС
$\begin{array}{c} C_{NC(OFF)},\\ C_{NO(OFF)} \end{array}$	NC, NO OFF capacitance	V_{NC} or $V_{NO} = V_{+}$ or GND, Switch OFF,	See Figure 13	25°C	5 V		23		pF
C _{NC(ON)} , C _{NO(ON)}	NC, NO ON capacitance	V_{NC} or $V_{NO} = V_{+}$ or GND, Switch ON,	See Figure 13	25°C	5 V		84		pF
C _{COM(ON)}	COM ON capacitance	$V_{COM} = V_+ \text{ or GND},$ Switch ON,	See Figure 13	25°C	5 V		84		pF
C _{IN}	Digital input capacitance	$V_{IN} = V_+ \text{ or } GND,$	See Figure 13	25°C	5 V		2.1		pF
BW	Bandwidth	$R_L = 50 \Omega$, Switch ON,	See Figure 16	25°C	5 V		100		MHz
O _{ISO}	OFF isolation	$\begin{array}{l} R_{L}=50\ \Omega,\\ f=1\ MHz, \end{array}$	Switch OFF, See Figure 17	25°C	5 V		-65		dB
X _{TALK}	Crosstalk	$\begin{array}{l} R_{L}=50\ \Omega,\\ f=1\ MHz, \end{array}$	Switch ON, See Figure 18	25°C	5 V		-65		dB
THD	Total harmonic distortion	$R_L = 600 \Omega,$ $C_L = 50 pF,$	f = 600 Hz to 20 kHz, See Figure 19	25°C	5 V		0.01%		
SUPPLY		· · ·		•					
	De sitis e surrels surrent		Quittele ON au OFF	25°C				0.1	
I ₊	Positive supply current	$V_{IN} = V_+ \text{ or GND},$	Switch ON or OFF	Full	5.5 V			0.5	μA

6.6 Electrical Characteristics for 3.3-V Supply

 $V_{+} = 3 V$ to 3.6 V and $T_{A} = -40^{\circ}C$ to $+125^{\circ}C$ (unless otherwise noted)

	PARAMETER	TEST CON	DITIONS	T _A	V.	MIN	TYP ⁽¹⁾	MAX	UNIT
ANALOG	SWITCH								
V _{COM} , V _{NO} ,V _{NC}	Analog signal range					0		V_{+}	V
r	Peak ON-state resistance	$0 \le V_{NO} \text{ or } V_{NC} \le V_{+},$	Switch ON,	25°C	3 V		1.35	2.2	Ω
r _{peak}	Fear On-State resistance	$I_{COM} = -24 \text{ mA},$	See Figure 10	Full	5 V			2.2	12
-	ON-state resistance	V_{NO} or $V_{NC} = 2 V$,	Switch ON,	25°C	3 V		1.15	1.8	Ω
r _{on}	UN-SIGLE TESISIGNCE	$I_{COM} = -24 \text{ mA},$	See Figure 10	Full	3 V			1.8	12
Δr_{on}	ON-state resistance match between channels	$\label{eq:VNC} \begin{array}{l} V_{NO} \text{ or } V_{NC} = 2 \text{ V}, \ 0.8 \text{ V}, \\ I_{COM} = -24 \text{ mA}, \end{array}$	Switch ON, See Figure 10	25°C	3 V		0.11		Ω
	01	$0 \le V_{NO} \text{ or } V_{NC} \le V_+,$ $I_{COM} = -24 \text{ mA},$	Switch ON,	25°C	0.14		0.225		
r _{on(flat)}	ON-state resistance flatness	$\label{eq:VNC} \begin{array}{l} V_{NO} \text{ or } V_{NC} = 2 \text{ V}, \ 0.8 \text{ V}, \\ I_{COM} = -24 \text{ mA}, \end{array}$	See Figure 10	25°C	3 V		0.25		Ω
I _{NC(OFF)} , I _{NO(OFF)}	NC, NO OFF leakage current		Switch OFF, See Figure 11	25°C	3.6 V		0.2		nA
I _{NC(ON)} , I _{NO(ON)}	NC, NO ON leakage current	V_{NC} or $V_{NO} = 3 V$, $V_{COM} = Open$,	Switch ON, See Figure 12	25°C	3.6 V		2.8		nA
I _{COM(ON)}	COM ON leakage current	V_{NC} or V_{NO} = 3 V or Open, V_{COM} = 3 V,	Switch ON, See Figure 12	25°C	3.6 V		0.47		nA

(1) $T_A = 25^{\circ}C$

6



Electrical Characteristics for 3.3-V Supply (continued)

 V_{\star} = 3 V to 3.6 V and T_{A} = -40°C to +125°C (unless otherwise noted)

	PARAMETER	TEST CON	IDITIONS	TA	٧,	MIN	TYP ⁽¹⁾	MAX	UNIT
DIGITAL I	NPUTS (IN)			1					
VIH	Input logic high			Full		2		5.5	V
VIL	Input logic low			Full		0		0.6	V
I _{IH} , I _{IL}	Input leakage current	V _{IN} = 5.5 V or 0		Full	3.6 V	-1		1	μA
DYNAMIC	;								
+	Turn-on time	$V_{COM} = V_+,$	C _L = 35 pF,	25°C	3 V to		30	40	ns
t _{ON}	rum-on ume	$R_L = 50 \ \Omega$	See Figure 15	Full	3.6 V			55	115
+	Turn-off time	$V_{COM} = V_+,$	C _L = 35 pF,	25°C	3 V to		20	25	ns
t _{OFF}		$R_L = 50 \ \Omega$	See Figure 15	Full	3.6 V			40	115
	Break-before-make time	$V_{NC} = V_{NO} = V_{+} / 2,$	C _L = 35 pF,	25°C	3 V to	1	21	29	
t _{BBM}	Dreak-Delore-make time	$R_L = 50 \ \Omega$	See Figure 16	Full	3.6 V	1			ns
Q _C	Charge injection	$C_L = 1 \text{ nF}, V_{GEN} = 0 \text{ V}$	See Figure 19	25°C	3.3 V		20		рС
$\begin{array}{c} C_{NC(OFF)},\\ C_{NO(OFF)} \end{array}$	NC, NO OFF capacitance	V_{NC} or $V_{NO} = V_{+}$ or GND, Switch OFF	See Figure 13	25°C	3.3 V		23		pF
C _{NC(ON)} , C _{NO(ON)}	NC, NO ON capacitance	V_{NC} or $V_{NO} = V_{+}$ or GND, Switch ON	See Figure 13	25°C	3.3 V		84		pF
C _{COM(ON)}	COM ON capacitance	$V_{COM} = V_{+}$ or GND, Switch ON	See Figure 13	25°C	3.3 V		84		pF
C _{IN}	Digital input capacitance	$V_{IN} = V_{+} \text{ or } GND$	See Figure 13	25°C	3.3 V		2.1		pF
BW	Bandwidth	$R_L = 50 \Omega,$ Switch ON	See Figure 16	25°C	3.3 V		100		MHz
O _{ISO}	OFF isolation	$\begin{array}{l} R_{L} = 50 \ \Omega, \\ f = 1 \ MHz \end{array}$	Switch OFF, See Figure 17	25°C	3.3 V		-65		dB
X _{TALK}	Crosstalk	$\begin{array}{l} R_{L} = 50 \ \Omega, \\ f = 1 \ MHz \end{array}$	Switch ON, See Figure 18	25°C	3.3 V		-65		dB
THD	Total harmonic distortion	$ \begin{array}{l} R_{L} = 600 \; \Omega, \\ C_{L} = 50 \; pF \end{array} $	f = 600 Hz to 20 kHz, See Figure 19	25°C	3.3 V		0.015%		
SUPPLY									
1	Positive supply current	$V_{IN} = V_{+}$ or GND	Switch ON or OFF	25°C	3.6 V			0.1	μA
I ₊	r usilive supply currell			Full	5.0 v			0.5	μΑ

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6.7 Electrical Characteristics For 2.5-V Supply

 $V_{_{+}}$ = 2.3 V to 2.7 V and T_{A} = –40°C to +125°C (unless otherwise noted)

	PARAMETER	TEST COND	ITIONS	T _A	۷.	MIN	TYP ⁽¹⁾	MAX	UNIT
ANALOG S	SWITCH								
V _{COM} , V _{NO} ,V _{NC}	Analog signal range					0		V_{+}	۷
r _{peak}	Peak ON-state resistance	$0 \le V_{NO} \text{ or } V_{NC} \le V_+,$ $I_{COM} = -8 \text{ mA}$	Switch ON, See Figure 10	25°C Full	2.5 V		1.7	2.9 2.9	Ω
r _{on}	ON-state resistance	V_{NO} or V_{NC} = 1.8 V, I_{COM} = -8 mA	Switch ON, See Figure 10	25°C Full	2.5 V		1.45	2.3 2.3	Ω
Δr_{on}	ON-state resistance match between channels	V_{NO} or V_{NC} = 0.8 V, 1.8 V, I_{COM} = -8 mA	Switch ON, See Figure 10	25°C	2.5 V		0.7		Ω
r	ON-state resistance flatness	$0 \le V_{NO} \text{ or } V_{NC} \le V_+,$ $I_{COM} = -8 \text{ mA}$	Switch ON,	25°C	2.5 V		0.5		Ω
r _{on(flat)}		$V_{NO} \text{ or } V_{NC}$ = 0.8 V, 1.8 V, I_{COM} = –8 mA	See Figure 10	25°C	2.5 V		0.45		12
I _{NC(OFF)} , I _{NO(OFF)}	NC, NO Off leakage current		Switch OFF, See Figure 11	25°C	2.7 V		0.2		nA
I _{NC(ON)} , I _{NO(ON)}	NC, NO On leakage current	V_{NC} or V_{NO} = 2.3 V, V_{COM} = Open	Switch ON, See Figure 12	25°C	2.7 V		2.8		nA
I _{COM(ON)}	COM On leakage current	V_{NC} or V_{NO} = 2.3 V or Open, V_{COM} = 2.3 V	Switch ON, See Figure 12	25°C	2.7 V		0.47		nA
DIGITAL IN	NPUTS (IN)			-					
V _{IH}	Input logic high			Full		1.8		5.5	V
V _{IL}	Input logic low			Full		0	0.6		V
I _{IH} , I _{IL}	Input leakage current	V _{IN} = 5.5 V or 0		Full	2.7 V	-1		1	μA
DYNAMIC									
t _{on}	Turn-on time	$V_{COM} = V_+,$ $R_L = 50 \ \Omega,$	C _L = 35 pF, See Figure 15	25°C Full	2.3 V to 2.7 V		40	55 70	ns
t _{OFF}	Turn-off time	$V_{COM} = V_+,$ $R_L = 50 \Omega,$	C _L = 35 pF, See Figure 15	25°C Full	2.3 V to 2.7 V		30	40 55	ns
t _{BBM}	Break-before-make time	$V_{NC} = V_{NO} = V_{+} / 2,$ $R_{L} = 50 \ \Omega,$	C _L = 35 pF, See Figure 16	25°C Full	2.3 V to 2.7 V	1	33	39	ns
Q _C	Charge injection	C _L = 1 nF, V _{GEN} = 0 V,	See Figure 19	25°C	2.5 V	-	13		рС
C _{NC(OFF)} , C _{NO(OFF)}	NC, NO OFF capacitance	V_{NC} or $V_{\text{NO}} = V_+$ or GND, Switch OFF,	See Figure 14	25°C	2.5 V		23		pG
C _{NC(ON)} , C _{NO(ON)}	NC, NO ON capacitance	V_{NC} or $V_{NO} = V_{+}$ or GND, Switch ON,	See Figure 14	25°C	2.5 V		84		pF
C _{COM(ON)}	COM ON capacitance	$V_{COM} = V_{+}$ or GND, Switch ON,	See Figure 14	25°C	2.5 V		84		pF
CIN	Digital input capacitance	$V_{IN} = V_{+}$ or GND,	See Figure 14	25°C	2.5 V		2.1		pF
BW	Bandwidth	$R_L = 50 \Omega,$ Switch ON,	See Figure 16	25°C	2.5 V		100		MHz
O _{ISO}	OFF isolation	$ \begin{array}{l} R_{L} = 50 \ \Omega, \\ f = 1 \ MHz, \end{array} $	Switch OFF, See Figure 17	25°C	2.5 V		-64		dB
X _{TALK}	Crosstalk	$ \begin{array}{l} R_{L} = 50 \ \Omega, \\ f = 1 \ MHz, \end{array} $	Switch ON, See Figure 18	25°C	2.5 V		-64		dB
THD	Total harmonic distortion		f = 600 Hz to 20 kHz, See Figure 19	25°C	2.5 V		0.025%		
SUPPLY									
	Positive supply current	$V_{IN} = V_{+}$ or GND,	Switch ON or OFF	25°C	2.7 V			0.1	μA

(1) $T_A = 25^{\circ}C$

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TS5A3159-Q1 SCDS336C – NOVEMBER 2012 – REVISED OCTOBER 2016

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6.8 Electrical Characteristics For 1.8-V Supply

 $V_{+} = 1.65$ V to 1.95 V and $T_{A} = -40$ °C to +125 °C (unless otherwise noted

	PARAMETER	TEST COND	TIONS	TA	V.	MIN	TYP ⁽¹⁾	MAX	UNIT
ANALOG	SWITCH								
V _{COM} , V _{NO} ,V _{NC}	Analog signal range					0		V_{+}	V
r _{peak}	Peak ON-state resistance	$0 \le V_{NO} \text{ or } V_{NC} \le V_+,$ $I_{COM} = -2 \text{ mA}$	Switch ON, See Figure 10	25°C Full	1.8 V		4	5.2 5.2	Ω
r _{on}	ON-state resistance	V_{NO} or $V_{NC} = 1.5 V$, $I_{COM} = -2 mA$	Switch ON, See Figure 10	25°C Full	1.8 V		1.7	3.5 3.5	Ω
Δr _{on}	ON-state resistance match between channels	V_{NO} or V_{NC} = 0.6 V, 1.5 V, I_{COM} = -2 mA	Switch ON, See Figure 10	25°C Full	1.8 V		0.7		Ω
		$0 \le V_{NO} \text{ or } V_{NC} \le V_+,$ $I_{COM} = -2 \text{ mA}$		25°C Full	-				
r _{on(flat)}	ON-state resistance flatness	$\frac{V_{NO} \text{ or } V_{NC} = 0.6 \text{ V}, 1.5 \text{ V},}{I_{COM} = -2 \text{ mA}}$	Switch ON, See Figure 11	25°C	1.8 V		1.85 0.9		Ω
I _{NC(OFF)} , I _{NO(OFF)}	NC, NO Off leakage current	$V_{NC} \text{ or } V_{NO} = 1.65 \text{ V},$ $V_{COM} = 0$	Switch OFF, See Figure 11	Full 25°C	1.95 V		0.9 0.2		nA
I _{NC(ON)} , I _{NO(ON)}	NC, NO On leakage current	V_{NC} or V_{NO} = 1.65 V, V_{COM} = Open	Switch ON, See Figure 12	25°C	1.95 V		2.8		nA
I _{COM(ON)}	COM On leakage current	V_{NC} or V_{NO} = 1.65 V or Open, V_{COM} = 1.65 V	Switch ON, See Figure 12	25°C	1.95 V		0.47		nA
DIGITAL I	NPUTS (IN)	1							
V _{IH}	Input logic high			Full		1.5		5.5	V
V _{IL}	Input logic low			Full		0		0.6	V
I _{IH} , I _{IL}	Input leakage current	$V_{IN} = 5.5 V \text{ or } 0$		Full	1.95 V	-1		1	μA
DYNAMIC									
t _{ON}	Turn-on time	$V_{COM} = V_+,$ $R_1 = 50 \Omega,$	C _L = 35 pF, See Figure 15	25°C Full	1.65 V to 1.95 V		65	70 95	ns
			-				40		-
t _{OFF}	Turn-off time		C _L = 35 pF, See Figure 15	25°C Full	1.65 V to 1.95 V		40	55 70	ns
t _{BBM}	Break-before-make time	$V_{NC} = V_{NO} = V_{+} / 2,$ $R_{L} = 50 \ \Omega,$	C _L = 35 pF, See Figure 15	25°C Full	1.65 V to 1.95 V	1 0.5	60	72	ns
Q _C	Charge injection	C _L = 1 nF, V _{GEN} = 0 V,	See Figure 19	25°C	1.8 V	0.0	13		pC
C _{NC(OFF)} , C _{NO(OFF)}	NC, NO OFF capacitance	V_{NC} or $V_{NO} = V_+$ or GND, Switch OFF,	See Figure 14	25°C	1.8 V		23		pF
C _{NC(ON)} , C _{NO(ON)}	NC, NO ON capacitance	V_{NC} or $V_{NO} = V_{+}$ or GND, Switch ON,	See Figure 14	25°C	1.8 V		84		pF
C _{COM(ON)}	COM ON capacitance	$V_{COM} = V_+ \text{ or GND},$ Switch ON,	See Figure 14	25°C	1.8 V		84		pF
CIN	Digital input capacitance	$V_{IN} = V_+ \text{ or } GND,$	See Figure 14	25°C	1.8 V		2.1		pF
BW	Bandwidth	$R_L = 50 \Omega,$ Switch ON,	See Figure 16	25°C	1.8 V		100		MHz
O _{ISO}	OFF isolation	$\begin{array}{l} R_{L} = 50 \ \Omega, \\ f = 1 \ MHz, \end{array}$	Switch OFF, See Figure 17	25°C	1.8 V		-63		dB
X _{TALK}	Crosstalk	$\begin{array}{l} R_{L} = 50 \ \Omega, \\ f = 1 \ MHz, \end{array}$	Switch ON, See Figure 18	25°C	1.8 V		-63		dB
SUPPLY				1	· · · · · ·				
I+	Positive supply current	$V_{IN} = V_+$ or GND,	Switch ON or OFF	25°C Full	1.95 V			0.1	μA

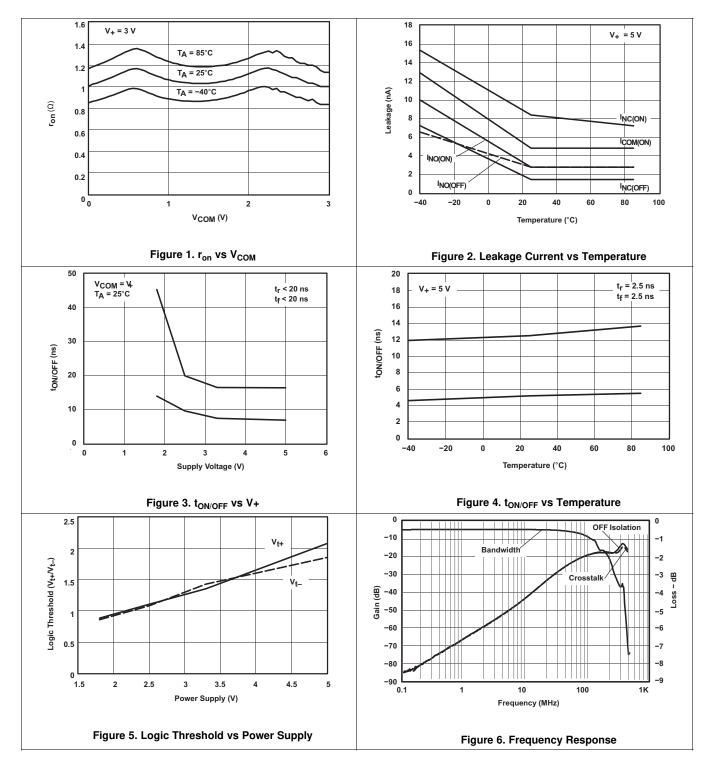
(1) $T_A = 25^{\circ}C$

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TS5A3159-Q1 SCDS336C-NOVEMBER 2012-REVISED OCTOBER 2016

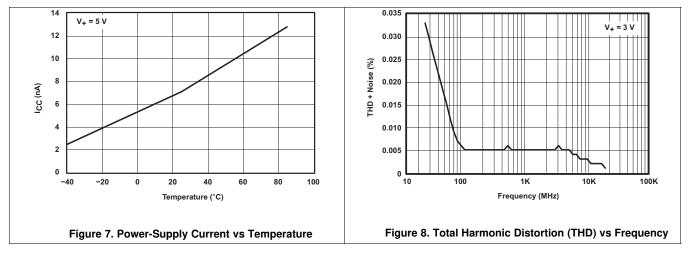
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6.9 Typical Characteristics





Typical Characteristics (continued)



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7 Parameter Measurement Information

Table 1. Parameter Description

VGOM Voltage at COM Vac Voltage at NC Vio Voltage at NC ran Resistance between COM and NC or COM and NO ports, when the channel is ON fpeak Peak ON-state resistance over a specified voltage range Aron Difference of r_on between channels Torn(Ital) Difference of r_on between channels Internet of r_on between the maximum and minimum value of r_on in a channel over the specified range of conditions Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF state under worst-case input and output conditions NacOFF) Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the ON state and the output (COM) being open NacON Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the ON state and the output (COM) being open NacON Leakage current measured at the COM port, with the corresponding channel (COM to NC or COM to NC) in the ON state and the output (NC or NO) being open Via Minimum input voltage for logic low for the control input (IN) Via Minimum input voltage for logic low for the control input (IN) Via Leakage current measured at IN Via Leakage current measured in IN Via Leak	SYMBOL	DESCRIPTION
VNO Voltage at NO Fen Resistance between COM and NC or COM and NO ports, when the channel is ON Peak ON-state resistance over a specified voltage range Difference of r _{co} between channels Oriflerine of r _{co} between the maximum and minimum value of r _{co} in a channel over the specified range of conditions NoticoFFI Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF state under worst-case input and output conditions NotiCoFFI Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF state under worst-case input and output conditions NotiCoFFI Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the ON state and the output (COM) being open Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the ON state and the output (COM) Leakage current measured at the COM port, with the corresponding channel (NO to COM to NC) in the ON state and the output (COM) Leakage current measured at the COM port, with the corresponding channel (COM to NO or COM to NC) in the ON state and the output (NC or NO) being open ViH Minimum input voltage for logic low for the control input (IN) ViL Minimum input voltage for logic low for the control input (IN) ViL Minimum input voltage for logic low for the control input (IN) ViL Minimum input volt	V _{COM}	Voltage at COM
Resistance between COM and NC or COM and NO ports, when the channel is ON Speak Peak ON-state resistance over a specified voltage range Argon Difference of ron, between channels Om(flat) Difference between the maximum and minimum value of ron in a channel over the specified range of conditions Inc(ICFF) Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF state under worst-case input and output conditions Inc(ICFF) Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF state under worst-case input and output conditions Inc(ICFF) Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the ON state and the output (COM) being open Leakage current measured at the OD port, with the corresponding channel (NO to COM) in the ON state and the output (COM) being open Leakage current measured at the COM port, with the corresponding channel (COM to NO or COM to NC) in the ON state and the output (NC on NO) being open VH Minimum input voltage for logic high for the control input (IN) VL Minimum input voltage for logic high for the control input (IN) VL Minimum input voltage for logic high for the control input (IN) VL Minimum input voltage for logic high for the control input (IN) VL Minimum input voltage for logic now for the control input (IN) <td>V_{NC}</td> <td>Voltage at NC</td>	V _{NC}	Voltage at NC
Peak ON-state resistance over a specified voltage range Argn Difference of rgn between channels ron(flat) Difference of rgn between channels Not(OFF) Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF state under worst-case input and output conditions Not(OFF) Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF state under worst-case input and output conditions Not(OFF) Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the ON state and the output (COM) being open Not(ON) Leakage current measured at the COM port, with the corresponding channel (NC to COM) in the ON state and the output (COM) being open VH Minimum input voltage for logic logic high for the control input (IN) VH Minimum input voltage for logic low for the control input (IN) VN Voltage at IN Urm-on time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning OFF. Term-off time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning OFF. Greff Turm-oft time for the switch. This parameter	V _{NO}	Voltage at NO
Arm Difference of r _{on} between channels Arm Difference between the maximum and minimum value of r _{on} in a channel over the specified range of conditions Iver(Int) Difference between the maximum and minimum value of r _{on} in a channel over the specified range of conditions Iver(OFF) Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF state under worst-case input and output conditions Iver(OFF) Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the ON state and the output (COM) being open Iver(ON) Leakage current measured at the NC port, with the corresponding channel (NO to COM) in the ON state and the output (COM) being open Iver(ON) Leakage current measured at the COM port, with the corresponding channel (COM to NO or COM to NC) in the ON state and the output (COM) being open VH Minimum input voltage for logic low for the control input (IN) VH Minimum input voltage for logic low for the control input (IN) VN Voltage at IN Import films for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning OFF. Teak-before-make time. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) sig	r _{on}	Resistance between COM and NC or COM and NO ports, when the channel is ON
Image: ron(IIIa1) Difference between the maximum and minimum value of r _{on} in a channel over the specified range of conditions Nc(OFF) Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF state under worst-case input and output conditions Nc(OFF) Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF state under worst-case input and output conditions Nc(ON) Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the ON state and the output (COM) being open Nc(CN) Leakage current measured at the COM port, with the corresponding channel (NC to COM) in the ON state and the output (COM) being open Nc(CN) Leakage current measured at the COM port, with the corresponding channel (NC to COM to NC) in the ON state and the output (COM) (NC or NO) being open Vin Minimum input voltage for logic high for the control input (IN) Vin Minimum input voltage for logic low for the control input (IN) Vin Voltage at IN Init, I., L Leakage current measured at an analog outputs (COM, NC, or NO) signal, when the switch is turning ON. toFF Turn-oft time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning ON. Qc Charge injectin is a measured under	r _{peak}	Peak ON-state resistance over a specified voltage range
Incomp Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF state under worst-case input and output conditions INO(OFF) Leakage current measured at the NO port, with the corresponding channel (NO to COM) in the OFF state under worst-case input and output conditions INC(ON) Leakage current measured at the NO port, with the corresponding channel (NO to COM) in the ON state and the output (COM) being open INC(ON) Leakage current measured at the NO port, with the corresponding channel (NO to COM) in the ON state and the output (COM) being open Icom(ON) Leakage current measured at the COM port, with the corresponding channel (NO to COM to NO or COM to NC) in the ON state and the output (NC or NO) being open ViH Minimum input voltage for logic high for the control input (IN) ViL Minimum input voltage for logic low for the control input (IN) ViL Urun-on time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning ON. torr-off time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning OFF. team Break-before-make time. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and an	Δr_{on}	Difference of ron between channels
INCICIPF) input and output conditions INCIGFF) Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF state under worst-case input and output conditions INCIGNI) Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the ON state and the output (COM) being open INCIGNI) Leakage current measured at the NC port, with the corresponding channel (NO to COM) in the ON state and the output (COM) being open Vin(ON) Leakage current measured at the COM port, with the corresponding channel (COM to NO or COM to NC) in the ON state and the output (NC or NO) being open Vin(N) Leakage current measured at the COM port, with the corresponding channel (COM to NO or COM to NC) in the ON state and the output (NC or NO) being open Vin(H) Minimum input voltage for logic high for the control input (IN) Vin(L) Minimum input voltage for logic low for the control input (IN) Vin L Leakage current measured at IN Lie Leakage current measured at IN Turn-off time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning OFF. Turn-off time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal,	ron(flat)	Difference between the maximum and minimum value of ron in a channel over the specified range of conditions
NNO(OFF) input and output conditions Inc(cN) Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the ON state and the output (COM) being open Icon(cN) Leakage current measured at the NO port, with the corresponding channel (NO to COM) in the ON state and the output (COM) being open Icon(cN) Leakage current measured at the COM port, with the corresponding channel (COM to NO or COM to NC) in the ON state and the output (NC or NO) being open ViH Minimum input voltage for logic high for the control input (IN) ViL Minimum input voltage for logic low for the control input (IN) VN Voltage at IN Leakage current measured at IN Leakage current measured at IN torn-of time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning ON. toFF Turn-oft time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning OFF. Break-before-make time. This parameter is measured under the specified range of conditions and by the propagation delay between the output of two adjacent analog channels (NC and NO), when the control signal changes state. Q _C Charge injection is a measurement of unwanted sig	I _{NC(OFF)}	
NNCION (COM) being open NNCION Leakage current measured at the NO port, with the corresponding channel (NO to COM) in the ON state and the output (COM) being open Icom(ON) Leakage current measured at the COM port, with the corresponding channel (COM to NO or COM to NC) in the ON state and the output (NC or NO) being open V _H Minimum input voltage for logic high for the control input (IN) V _H Minimum input voltage for logic high for the control input (IN) V _N Voltage at IN Leakage current measured at IN Leakage current measured at IN town Turn-on time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning ON. toFF Turn-off time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning ONF. tBBM Break-before-make time. This parameter is measured under the specified range of conditions and by the propagation delay between the output of two adjacent analog channels (NC and NO), when the control signal changes state. Q _C Charge injection is a measurement of unwanted signal coupling from the control (IN) input to the analog (NC, NO, or COM) output. This is measured in coulomb (C) and measured to tha charge induced due to switch	I _{NO(OFF)}	
INCION (COM) being open IcoM(ON) Leakage current measured at the COM port, with the corresponding channel (COM to NO or COM to NC) in the ON state and the output (NC or NO) being open VI _H Minimum input voltage for logic high for the control input (IN) VI _L Minimum input voltage for logic low for the control input (IN) VI _L Minimum input voltage for logic low for the control input (IN) VI _L Leakage current measured at IN town Turn-on time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning ON. toFF Turn-off time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning OFF. Break-before-make time. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning OFF. Break-before-make time. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning OFF. Charge injection is a measurement of unwanted signal coupling from the control (IN) input to the analog (NC, NO, or COM) output. This	I _{NC(ON)}	
Itercontroland the output (NC or NO) being open V_{H} Minimum input voltage for logic high for the control input (IN) V_{L} Minimum input voltage for logic low for the control input (IN) V_{IN} Voltage at IN V_{IN} Voltage at INLeakage current measured at INtotalTurn-on time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning ON.toFFTurn-off time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning ON.toFFTurn-off time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning OFF.tBeMBreak-before-make time. This parameter is measured under the specified range of conditions and by the propagation delay between the output of two adjacent analog channels (NC and NO), when the control (IN) input to the analog (NC, NO, or COM) output. This is measured in coulomb (C) and measured by the total charge induced due to switching of the control input. Charge injection, $Q_C = C_L \times \Delta V_O$, C_L is the load capacitance, and ΔV_O is the change in analog output voltage. $G_{NC(OFF)}$ Capacitance at the NC port when the corresponding channel (NC to COM) is OFF $C_{NC(OFF)}$ Capacitance at the NC port when the corresponding channel (NC to COM) is ON $C_{NC(ON)}$ Capacitance a	I _{NO(ON)}	
V _{IL} Minimum input voltage for logic low for the control input (IN) V _{IN} Voltage at IN I _{IH} , I _{IL} Leakage current measured at IN toN Turn-on time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning ON. toFF Turn-off time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning OFF. tBEM Break-before-make time. This parameter is measured under the specified range of conditions and by the propagation delay between the output of two adjacent analog channels (NC and NO), when the control signal changes state. Q _C Charge injection, Q _C = C _L × Δ _{Q_C} , C _L is the load capacitance, and Δ _{V_O} is the charge in analog output voltage. CNC(OFF) Capacitance at the NC port when the corresponding channel (NC to COM) is OFF CNC(OFF) Capacitance at the NC port when the corresponding channel (NC to COM) is ON C _{NC(ONF)} Capacitance at the NO port when the corresponding channel (NC to COM) is ON C _{NC(ONF)} Capacitance at the NC port when the corresponding channel (NC to COM) is ON C _{NO(ONI}) Capacitance at the NO port when the corresponding channel (NC to COM) is ON <	I _{COM(ON)}	
V _{IN} Voltage at IN I _{IH} , I _{IL} Leakage current measured at IN toN Turn-on time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning ON. toFF Turn-off time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning OFF. tBeak-before-make time. This parameter is measured under the specified range of conditions and by the propagation delay between the output of two adjacent analog channels (NC and NO), when the control signal changes state. Q _C Charge injection is a measurement of unwanted signal coupling from the control (IN) input to the analog (NC, NO, or COM) output. This is measured in coulomb (C) and measured by the total charge induced due to switching of the control input. Charge injection, Q _c = C _⊥ × ∆V _O , C _⊥ is the load capacitance, and ∆V _O is the change in analog output voltage. CNC(OFF) Capacitance at the NC port when the corresponding channel (NC to COM) is OFF CNC(OFF) Capacitance at the NC port when the corresponding channel (NC to COM) is ON C _{NC(OFF)} Capacitance at the NC port when the corresponding channel (NC to COM) is ON C _{NC(ON)} Capacitance at the NC port when the corresponding channel (NC to COM) is ON C _{NO(ON)}	V _{IH}	Minimum input voltage for logic high for the control input (IN)
I _{IH} , I _{IL} Leakage current measured at IN toN Turn-on time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning ON. toFF Turn-off time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning OFF. tBeBM Break-before-make time. This parameter is measured under the specified range of conditions and by the propagation delay between the output of two adjacent analog channels (NC and NO), when the control signal changes state. Q _C Charge injection is a measurement of unwanted signal coupling from the control (IN) input to the analog (NC, NO, or COM) output. This is measured in coulomb (C) and measured by the total charge induced due to switching of the control input. Charge injection, Q _C = C _L × AV _O , C _L is the load capacitance, and AV _O is the change in analog output voltage. CN _{CIOFFF} Capacitance at the NC port when the corresponding channel (NC to COM) is OFF CN _{OION} Capacitance at the NO port when the corresponding channel (NC to COM) is ON C _{OMION} Capacitance at the NO port when the corresponding channel (NC to COM to NO) is ON C _{OMION} Capacitance at the COM port when the corresponding channel (NC to COM to NO) is ON C _{OMION} Capacitance at the COM port when th	V _{IL}	Minimum input voltage for logic low for the control input (IN)
Turn-on time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning ON. t_{OFF} Turn-off time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning OFF. t_{BEM} Break-before-make time. This parameter is measured under the specified range of conditions and by the propagation delay between the output of two adjacent analog channels (NC and NO), when the control signal changes state. Q_C Charge injection is a measurement of unwanted signal coupling from the control (IN) input to the analog (NC, NO, or COM) output. This is measured in coulomb (C) and measured by the total charge induced due to switching of the control input. Charge injection, $Q_C = C_L \times \Delta V_O$, C_L is the load capacitance, and ΔV_O is the change in analog output voltage. $C_{NC(OFF)}$ Capacitance at the NC port when the corresponding channel (NC to COM) is OFF $C_{NQ(OFF)}$ Capacitance at the NC port when the corresponding channel (NC to COM) is ON $C_{OM(ON)}$ Capacitance at the NO port when the corresponding channel (NC to COM) is ON $C_{OM(ON)}$ Capacitance at the COM port when the corresponding channel (NC to NC or COM to NO) is ON C_{IN} Capacitance of IN O_{IN} Capacitance of IN O_{IN} Capacitance of IN O_{IN} Capacitance of IN O_{IN} Capacitance of IN O_{ISO} OFF isolation of the switch is a measurement OFF-state switch impedance.	V _{IN}	Voltage at IN
Ideal delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning ON. toFF Turn-off time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning OFF. tBBM Break-before-make time. This parameter is measured under the specified range of conditions and by the propagation delay between the output of two adjacent analog cutputs (COM, NC, or NO) signal, when the switch is turning OFF. tBBM Break-before-make time. This parameter is measured under the specified range of conditions and by the propagation delay between the output of two adjacent analog channels (NC and NO), when the control signal changes state. Q _C Charge injection is a measurement of unwanted signal coupling from the control (IN) input to the analog (NC, NO, or COM) output. This is measured in coulomb (C) and measured by the total charge induced due to switching of the control input. Charge injection, Q _C = C _L × ΔV _O , C _L is the load capacitance, and ΔV _O is the change in analog output voltage. C _{NC(OFF)} Capacitance at the NC port when the corresponding channel (NC to COM) is OFF C _{NO(OFF)} Capacitance at the NO port when the corresponding channel (NO to COM) is ON C _{COM(ON)} Capacitance at the NO port when the corresponding channel (NO to COM) is ON C _{COM(ON)} Capacitance at the COM port when the corresponding channel (NO to COM) is ON	I _{IH} , I _{IL}	Leakage current measured at IN
^{IOFF} delay between the digital control (IN) signal and analog outputs (COM, NC, or NO) signal, when the switch is turning OFF. tBBM Break-before-make time. This parameter is measured under the specified range of conditions and by the propagation delay between the output of two adjacent analog channels (NC and NO), when the control signal changes state. Q _C Charge injection is a measurement of unwanted signal coupling from the control (IN) input to the analog (NC, NO, or COM) output. This is measured in coulomb (C) and measured by the total charge induced due to switching of the control input. Charge injection, Q _C = C _L × ΔV _O , C _L is the load capacitance, and ΔV _O is the change in analog output voltage. C _{NC(OFF)} Capacitance at the NC port when the corresponding channel (NC to COM) is OFF C _{NO(OFF)} Capacitance at the NC port when the corresponding channel (NC to COM) is ON C _{NO(ON)} Capacitance at the NO port when the corresponding channel (NC to COM) is ON C _{OM(ON)} Capacitance at the COM port when the corresponding channel (NC to COM) is ON Cost Capacitance at the COM port when the corresponding channel (NC to COM) is ON Cost Capacitance at the COM port when the corresponding channel (NC to COM to NO) is ON Cost Capacitance at the COM port when the corresponding channel (NC to COM to NO) is ON Cost Capacitance of IN O _{ISO} OFF isolation of the switch is a measurement OFF-state switch im	t _{ON}	
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CNO(OFF) Capacitance at the NO port when the corresponding channel (NO to COM) is OFF CNC(ON) Capacitance at the NC port when the corresponding channel (NC to COM) is ON CNO(ON) Capacitance at the NO port when the corresponding channel (NO to COM) is ON CNO(ON) Capacitance at the COM port when the corresponding channel (NO to COM) is ON CCOM(ON) Capacitance at the COM port when the corresponding channel (COM to NC or COM to NO) is ON CIN Capacitance of IN OISO OFF isolation of the switch is a measurement OFF-state switch impedance. This is measured in dB in a specific frequency, with the corresponding channel (NC to COM or NO to COM) in the OFF state. XTALK Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC to NO or NO to NC). This is measured in a specific frequency and in dB. Bundwidth of the switch. This is the frequency in which the gain of an ON channel is -3 dB below the DC gain. I ₊ Static power-supply current with the control (IN) pin at V ₊ or GND	Q _C	output. This is measured in coulomb (C) and measured by the total charge induced due to switching of the control input.
CNC(ON) Capacitance at the NC port when the corresponding channel (NC to COM) is ON C _{NO(ON)} Capacitance at the NO port when the corresponding channel (NO to COM) is ON C _{COM(ON)} Capacitance at the COM port when the corresponding channel (COM to NC or COM to NO) is ON C _{COM(ON)} Capacitance at the COM port when the corresponding channel (COM to NC or COM to NO) is ON C _{IN} Capacitance of IN O _{ISO} OFF isolation of the switch is a measurement OFF-state switch impedance. This is measured in dB in a specific frequency, with the corresponding channel (NC to COM or NO to COM) in the OFF state. X _{TALK} Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC to NO or NO to NC). This is measured in a specific frequency and in dB. BW Bandwidth of the switch. This is the frequency in which the gain of an ON channel is -3 dB below the DC gain. I ₊ Static power-supply current with the control (IN) pin at V ₊ or GND	C _{NC(OFF)}	Capacitance at the NC port when the corresponding channel (NC to COM) is OFF
CNO(ON) Capacitance at the NO port when the corresponding channel (NO to COM) is ON C _{OM(ON)} Capacitance at the COM port when the corresponding channel (COM to NC or COM to NO) is ON C _{IN} Capacitance of IN O _{ISO} OFF isolation of the switch is a measurement OFF-state switch impedance. This is measured in dB in a specific frequency, with the corresponding channel (NC to COM or NO to COM) in the OFF state. X _{TALK} Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC to NO or NO to NC). This is measured in a specific frequency and in dB. BW Bandwidth of the switch. This is the frequency in which the gain of an ON channel is -3 dB below the DC gain. I ₊ Static power-supply current with the control (IN) pin at V ₊ or GND	C _{NO(OFF)}	Capacitance at the NO port when the corresponding channel (NO to COM) is OFF
C _{COM(ON)} Capacitance at the COM port when the corresponding channel (COM to NC or COM to NO) is ON C _{IN} Capacitance of IN O _{ISO} OFF isolation of the switch is a measurement OFF-state switch impedance. This is measured in dB in a specific frequency, with the corresponding channel (NC to COM or NO to COM) in the OFF state. X _{TALK} Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC to NO or NO to NC). This is measured in a specific frequency and in dB. BW Bandwidth of the switch. This is the frequency in which the gain of an ON channel is -3 dB below the DC gain. I ₊ Static power-supply current with the control (IN) pin at V ₊ or GND	C _{NC(ON)}	Capacitance at the NC port when the corresponding channel (NC to COM) is ON
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OISO OFF isolation of the switch is a measurement OFF-state switch impedance. This is measured in dB in a specific frequency, with the corresponding channel (NC to COM or NO to COM) in the OFF state. XTALK Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC to NO or NO to NC). This is measured in a specific frequency and in dB. BW Bandwidth of the switch. This is the frequency in which the gain of an ON channel is -3 dB below the DC gain. I ₊ Static power-supply current with the control (IN) pin at V ₊ or GND	C _{COM(ON)}	Capacitance at the COM port when the corresponding channel (COM to NC or COM to NO) is ON
OISO with the corresponding channel (NC to COM or NO to COM) in the OFF state. XTALK Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC to NO or NO to NC). This is measured in a specific frequency and in dB. BW Bandwidth of the switch. This is the frequency in which the gain of an ON channel is -3 dB below the DC gain. I ₊ Static power-supply current with the control (IN) pin at V ₊ or GND	C _{IN}	Capacitance of IN
ATALK This is measured in a specific frequency and in dB. BW Bandwidth of the switch. This is the frequency in which the gain of an ON channel is -3 dB below the DC gain. I ₊ Static power-supply current with the control (IN) pin at V ₊ or GND	O _{ISO}	
I ₊ Static power-supply current with the control (IN) pin at V ₊ or GND	X _{TALK}	Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC to NO or NO to NC). This is measured in a specific frequency and in dB.
	BW	Bandwidth of the switch. This is the frequency in which the gain of an ON channel is -3 dB below the DC gain.
	I+	Static power-supply current with the control (IN) pin at V ₊ or GND
	ΔI_+	This is the increase in I_+ for each control (IN) input that is at the specified voltage, rather than at V ₊ or GND.

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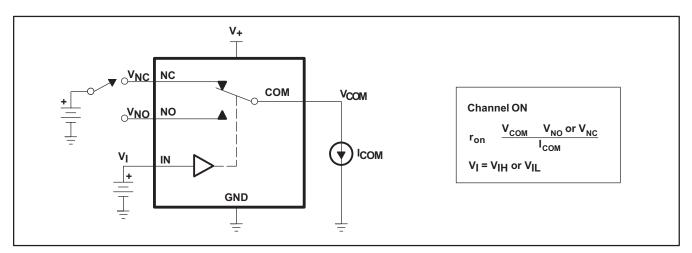


Figure 9. On-State Resistance (ron)

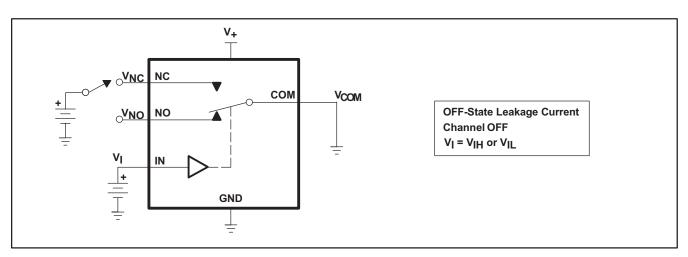
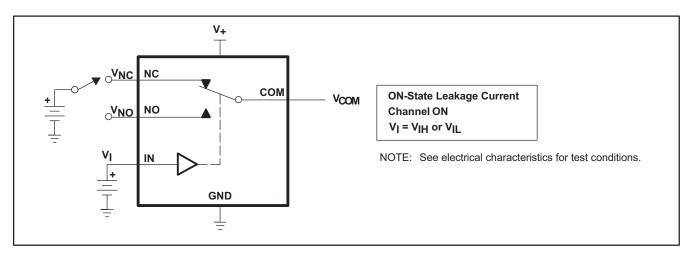
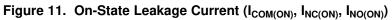


Figure 10. Off-State Leakage Current (I_{NC(OFF)}, I_{NO(OFF)})







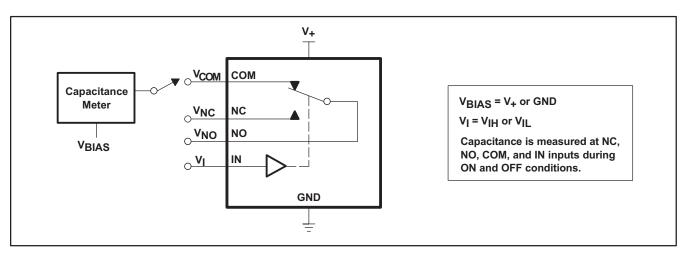
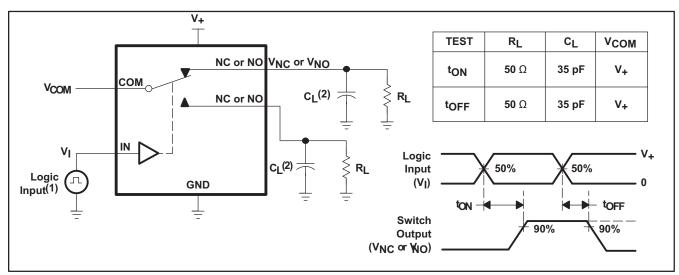


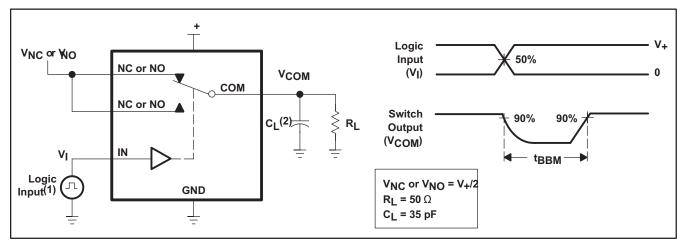
Figure 12. Capacitance (CI, C_{COM(ON)}, C_{NC(OFF)}, C_{NO(OFF)}, C_{NC(ON)}, C_{NO(ON)})



(1) All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f < 5 ns, t_f < 5 ns. (2) C_L includes probe and jig capacitance.

Figure 13. Turn-On (t_{ON}) and Turn-Off Time (t_{OFF})





(1) All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f < 5 ns. (2) C_L includes probe and jig capacitance.

Figure 14. Break-Before-Make Time (t_{BBM})

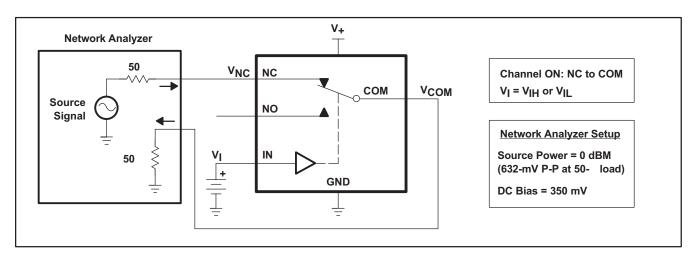


Figure 15. Bandwidth (BW)

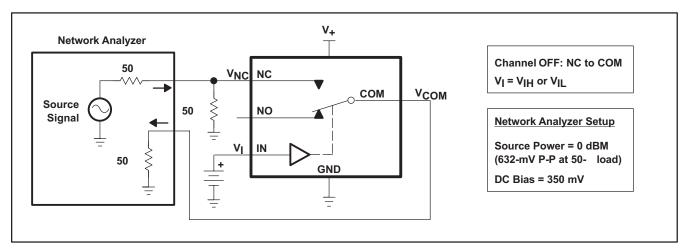


Figure 16. OFF Isolation (O_{ISO})

TS5A3159-Q1 SCDS336C - NOVEMBER 2012 - REVISED OCTOBER 2016



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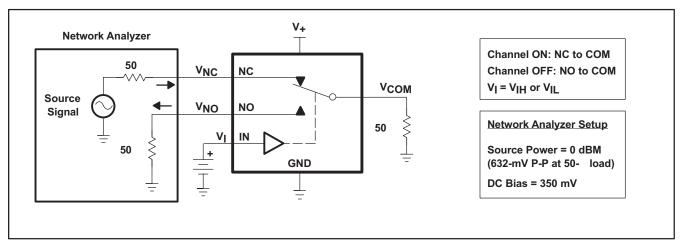
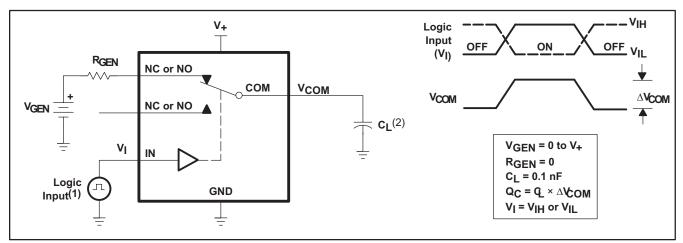
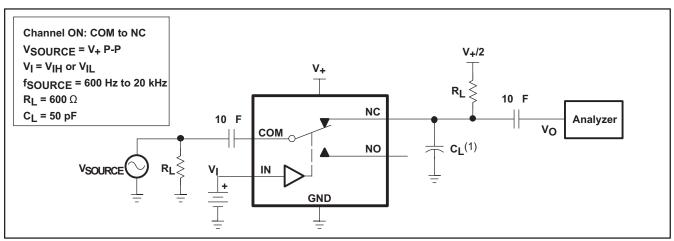


Figure 17. Crosstalk (X_{TALK})



(1) All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_r < 5 ns, t_f < 5 ns. (2) C_L includes probe and jig capacitance.





(1) $C_{\mbox{L}}$ includes probe and jig capacitance.

Figure 19. Total Harmonic Distortion (THD)

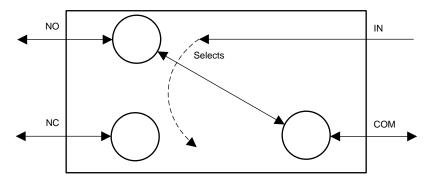


8 Detailed Description

8.1 Overview

The TS5A3159-Q1 is a single-pole double-throw (SPDT) analog switch designed to operate from 1.65 V to 5.5 V. Either the NO or the NC pin is shorted to the COM pin, depending on the logic level input to the IN pin.

8.2 Functional Block Diagram



8.3 Feature Description

The main feature of this device is the excellent total harmonic distortion performance and low power consumption. Additionally, the NO, NC, and COM pins can be used as either inputs or outputs.

CONFIGURATION	2:1 MULTIPLEXER / DEMULTIPLEXER (1 × SPDT)
Number of channels	1
ON-state resistance (ron)	1.3 Ω
ON-state resistance match (Δr_{on})	0.1 Ω
ON-state resistance flatness (ron(flat))	0.15 Ω
Turn on/turn off time (t _{ON} / t _{OFF})	20 ns / 15 ns
Break-before-make time (t _{BBM})	12 ns
Charge injection (Q _C)	36 pC
Bandwidth (BW)	100 MHz
OFF isolation (O _{ISO})	–65 dB at 1 MHz
Crosstalk (X _{TALK})	–65 dB at 1 MHz
Total harmonic distortion (THD)	0.01%
Leakage current (I _{NO(OFF)} / I _{NC(OFF)})	±6 nA
Package option	6-pin DBV

Table 2. Summary Of Characteristics⁽¹⁾

(1) $V_{+} = 5 V \text{ and } T_{A} = 25^{\circ}C$

8.4 Device Functional Modes

Table 3 lists the functions for the TS5A3159-Q1 device.

Table 3. Function Table

IN	NC TO COM, COM TO NC	NO TO COM, COM TO NO
L	ON	OFF
Н	OFF	ON



9 Applications and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

Analog switches are commonly used in battery powered applications to route audio signals. A typical use case is highlighted in Figure 20. The analog switch is supplied with 5 V and the control input is from a 5-V processor GPIO. In this case, there are no concerns related to excess power consumption.

9.2 Typical Application

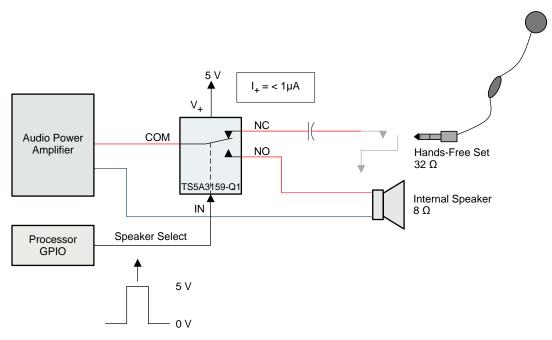


Figure 20. Typical Application Schematic

9.2.1 Design Requirements

In this application example, the device receives the control signal from a 5-V GPIO and common input from an Audio Power amplifier. The input is routed to either the Hands free set or the internal speaker depending upon the control signal.

9.2.2 Detailed Design Procedure

Since the control signal varies from 0 to 5 V (Vdd), there's no excess current consumption. However, if the control signal comes from lower voltage GPIOs while the V+ of TS5A3159 is connected to the battery whose voltage varies, it can lead to an excess current draw from the V+ suppl pin. Such a scenario requires the use of an external voltage level translator such as the SN74LVC1T45. For more information see *Preventing Excess Current Consumption on Analog Switches*, SCDA011.



Typical Application (continued)

9.2.3 Application Curve

The ON state resistance of the switch is a critical parameter to measure since it helps select the right switch for the application. The on state resistance versus the common voltage can be seen in Figure 21.

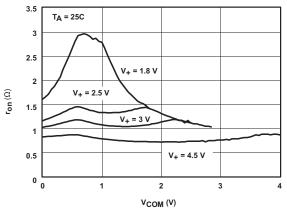


Figure 21. r_{on} vs V_{COM}

10 Power Supply Recommendations

Most systems have a common 3.3 V or 5 V rail that can supply the V+ pin of this device. If this is not available, a Switch-Mode-Power-Supply (SMPS) or a Linear Dropout Regulator (LDO) can supply this device from a higher voltage rail. Proper decouping of the supply rail is a must to avoid any spikes that may exceed the absolute ratings of the V+ pin of the device.

11 Layout

11.1 Layout Guidelines

TI recommends to keep signal lines as short as possible. Incorporation of microstrip or stripline techniques is also recommended when signal lines are greater than 1 inch in length. These traces must be designed with a characteristic impedance of either 50 Ω or 75 Ω , as required by the application. Do not place this device too close to high voltage switching components, as they may cause interference.

11.2 Layout Example

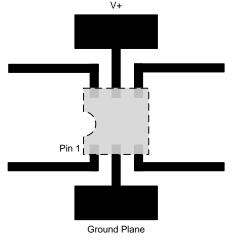


Figure 22. Layout Example

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12 Device and Documentation Support

12.1 Documentation Support

12.1.1 Related Documentation

For related documentation see the following:

Preventing Excess Current Consumption on Analog Switches, SCDA011

12.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.3 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E[™] Online Community *TI's Engineer-to-Engineer (E2E) Community.* Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.4 Trademarks

E2E is a trademark of Texas Instruments. All other trademarks are the property of their respective owners.

12.5 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

12.6 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



10-Dec-2020

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
TS5A3159QDBVRQ1	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	UAAQ	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(⁶⁾ Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF TS5A3159-Q1 :



PACKAGE OPTION ADDENDUM

10-Dec-2020

Catalog: TS5A3159

• Enhanced Product: TS5A3159-EP

NOTE: Qualified Version Definitions:

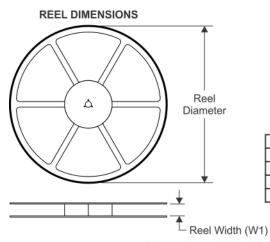
- Catalog TI's standard catalog product
- Enhanced Product Supports Defense, Aerospace and Medical Applications

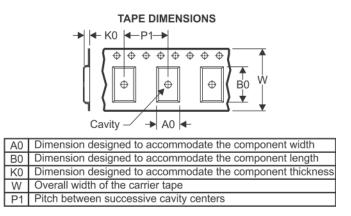
PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TS5A3159QDBVRQ1	SOT-23	DBV	6	3000	180.0	8.4	3.23	3.17	1.37	4.0	8.0	Q3

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PACKAGE MATERIALS INFORMATION

24-Apr-2020

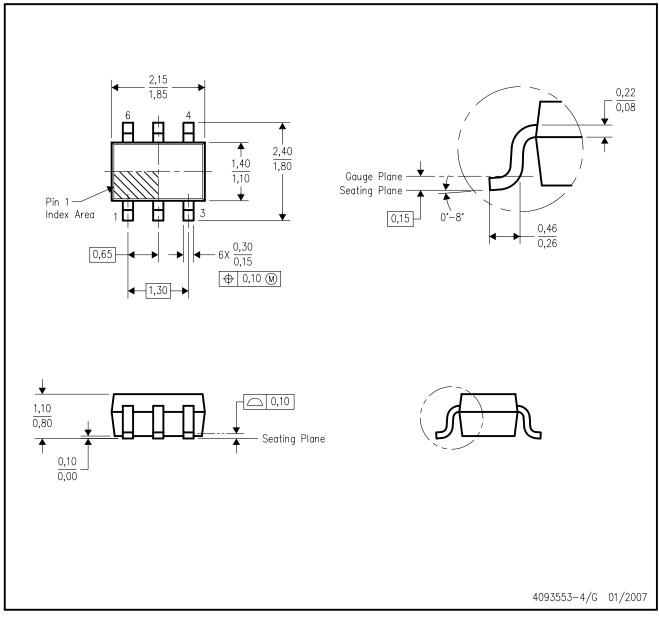


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TS5A3159QDBVRQ1	SOT-23	DBV	6	3000	202.0	201.0	28.0

DCK (R-PDSO-G6)

PLASTIC SMALL-OUTLINE PACKAGE



- NOTES: A. All linear dimensions are in millimeters.
 - B. This drawing is subject to change without notice.
 - C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.
 - D. Falls within JEDEC MO-203 variation AB.



DBV0006A



PACKAGE OUTLINE

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 This drawing is subject to change without notice.
 Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.25 per side.

- 4. Leads 1,2,3 may be wider than leads 4,5,6 for package orientation. 5. Refernce JEDEC MO-178.



DBV0006A

EXAMPLE BOARD LAYOUT

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

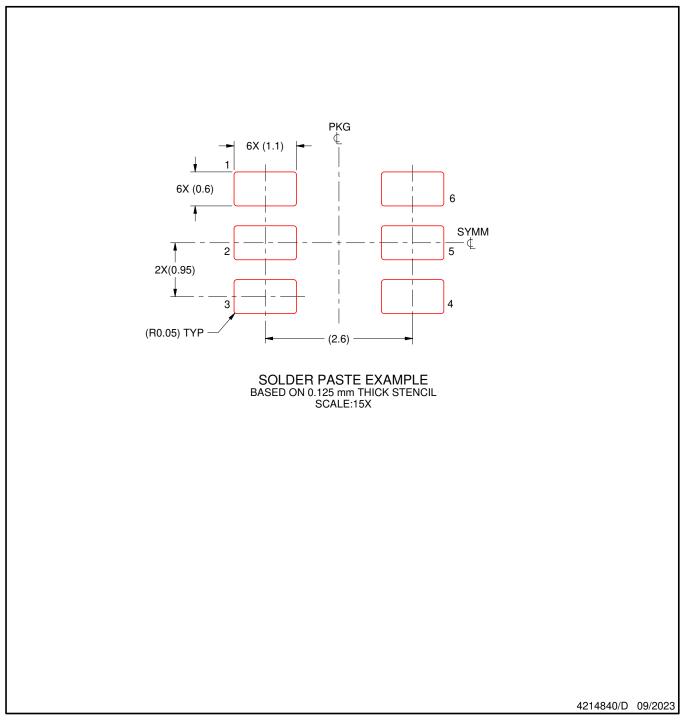


DBV0006A

EXAMPLE STENCIL DESIGN

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



NOTES: (continued)

9. Board assembly site may have different recommendations for stencil design.



^{8.} Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

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